Automated design error localization in RTL designs
Jenihhin, Maksim; **Tšepurov, Anton**; **Tihhomirov, Valentin**; **Raik, Jaan**; **Hantson, Hanno**; **Ubar, Raimund-Johannes**; Bartsch, Günter; Meza Escobar, Jorge Hernan; Wuttke, Heinz-Dietrich IEEE design & test of computers 2014 / p. 83-92 : ill
https://doi.org/10.1109/MDAT.2013.2271420 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Test synthesis with alternative graphs
Ubar, Raimund-Johannes IEEE design & test of computers 1996 / Spring, p. 48-57: ill